

# INFORMATION DISCLOSURE CITATION IN AN APPLICATION

 ATTY. DOCKET NO.  
61282-043

 SERIAL NO.  
10/698,532

 APPLICANT  
Takuya KOBAYASHI

 FILING DATE  
November 03, 2003

 GROUP  
~~2858~~ 2138

(PTO-1449)

## U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		US 6,065,145	05/18/2000	Lucent Technologies, Inc.	
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			

## FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes - Number - Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation	
						Yes	No
GI		JP 8-148293	05/27/1994	KAWASAKI STEEL CORP		(Japan w/English Abstract)	
SV		JP P2002-189063A	07/05/2002	HITACHI LTD		(Japan w/English Abstract)	
ka		JP 7-260899	10/13/1995	KAWASAKI STEEL CORP		(Japan w/English Abstract)	

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.

EXAMINER

DATE CONSIDERED

5-9-06

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.

# INFORMATION DISCLOSURE CITATION IN AN APPLICATION

 ATTY. DOCKET NO.  
61282-043

 SERIAL NO.  
10/698,532

 APPLICANT  
Takuya KOBAYASHI

 FILING DATE  
November 03, 2003

 GROUP  
2858 2138

(PTO-1449)

## U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			

## FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes-Number-Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation	
						Yes	No

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
40		Angela KRSTIC, et al., "Delay Fault Testing for VLSI Circuits", pp. 7-12, Kluwer Academic Publishers, 1998.

EXAMINER

DATE CONSIDERED

5-4-06

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 809. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.



SHEET 1 OF 1

INFORMATION DISCLOSURE  
CITATION IN AN  
APPLICATION

(PTO-1449)

ATTY. DOCKET NO.  
**061282-0043**SERIAL NO.  
**10/698,532**APPLICANT  
**Takuya KOBAYASHI**FILING DATE  
**November 03, 2003**GROUP  
**2133**

## U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
<i>gn</i>		US 6,829,573		Matsumoto et al.	Corresponds with CN 1232972 A
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			

## FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Code-Number + Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation	
<i>gn</i>		CN 1232972 A	10/27/1999	-	Corresponds with USP 6,829,573	CHINA (w/Abstract of Corresponding USP 6,829,573)	No
<i>gn</i>		JP 2001-165996 A	06/22/2001	MATSUSHITA ELECTRIC IND CO LTD		JAPAN (w/English Abstract)	
<i>gn</i>		JP 2001-74813 A	03/23/2001	TOKYO SHIBAURA ELECTRIC CO		JAPAN (w/English Abstract)	

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	

EXAMINER

*[Signature]*

DATE CONSIDERED

5-9-06

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered.  
Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.